

Product Change Notification / GDOS-04EWFZ700

Date:

07-Feb-2024

Product Category:

Crypto Memory

PCN Type:

Manufacturing Change

Notification Subject:

CCB 6792 Initial Notice: Qualification of MTAI as an additional assembly site for selected AT88SC0104CA, AT88SC0204CA, AT88SC0404CA and AT88SC0808CA device families available in 8L SOIC (.150in) package using CuPdAu wire.

Affected CPNs:

GDOS-04EWFZ700_Affected_CPN_02072024.pdf GDOS-04EWFZ700_Affected_CPN_02072024.csv

Notification Text:

PCN Status:Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of MTAI as an additional assembly site for selected AT88SC0104CA, AT88SC0204CA, AT88SC0404CA and AT88SC0808CA device families available in 8L SOIC (.150in) package using CuPdAu wire.

Pre and Post Change Summary:

	Pre C	hange	Post Change					
Assembly Site	(Shangha	ATX Semiconductor (Shanghai)Co. Ltd (ASSH)		conductor ai)Co. Ltd SH)	Microchip Technology Thailand (HQ) (MTAI)			
Wire Material	Au	PdCu	Au	PdCu	CuPdAu			
Die Attach Material	EN-4	EN-4900G		900G	QMI-519			
Molding Compound Material	G70	G700LY		OLY	G600V			
Lead-Frame Material	C1	94	C1	94	C194			
DAP Surface Prep	PI	PPF		PPF PPI		PF	Bare Cu	
Lead Plating	NiP	dAu	NiP	dAu	Matte tin			
Lead-Frame Design	See Pre and Post Change Comparison							

Impacts to Data Sheet:

None

Change ImpactNone

Reason for Change:To improve on-time delivery performance by qualifying MTAI as an additional assembly site.

Change Implementation Status: In Progress

Estimated Qualification Completion Date: May 2024

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

	February 2024							Ma	ay 20)24	
Workweek	0 5	0 6	0 7	0 8	0 9		1 8	1 9	2 0	2 1	2 2
Initial PCN Issue Date		х									
Qual Report Availability										х	
Final PCN Issue										х	

Date				
	 	 · · · ·	·	·

Method to Identify Change: Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History:

February 07, 2024: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN_GDOS-04EWFZ700_Pre_and_Post_Change_Summary.pdf PCN_GDOS-04EWFZ700_Qual_Plan.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.

If you wish to <u>change your PCN profile, including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

GDOS-04EWFZ700 - CCB 6792 Initial Notice: Qualification of MTAI as an additional assembly site for selected AT88SC0104CA, AT88SC0204CA, AT88SC0404CA and AT88SC0808CA device families available in 8L SOIC (.150in) package using CuPdAu wire.

Affected Catalog Part Numbers (CPN)

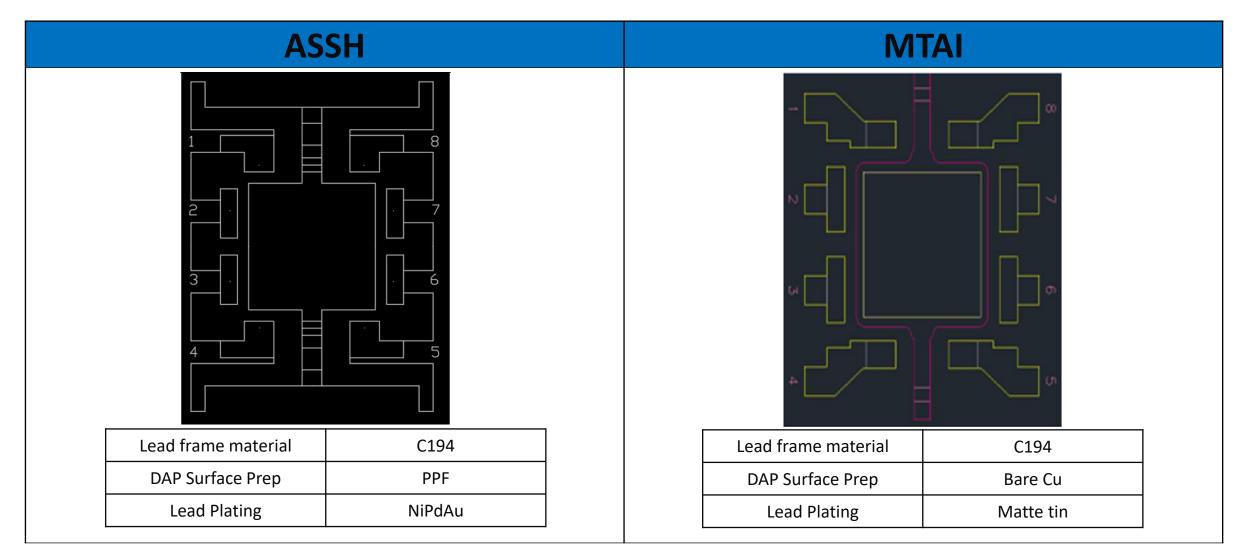
AT88SC0104CA-SH AT88SC0204CA-SH AT88SC0404CA-SH AT88SC0808CA-SH AT88SC0104CA-SH-T AT88SC0204CA-SH-T AT88SC0404CA-SH-T AT88SC0808CA-SH-T



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Pre and Post Change Summary - Lead Frame Comparison



*Note: Not fit to scale





QUALIFICATION PLAN SUMMARY

PCN #: GDOS-04EWFZ700

Date: January 17, 2024

Qualification of MTAI as an additional assembly site for selected AT88SC0104CA, AT88SC0204CA, AT88SC0404CA and AT88SC0808CA device families available in 8L SOIC (.150in) package using CuPdAu wire. Purpose: Qualification of MTAI as an additional assembly site for selected AT88SC0104CA, AT88SC0204CA, AT88SC0404CA and AT88SC0808CA device families available in 8L SOIC (.150in) package using CuPdAu wire.

CCB No.: 6792

	[1				
	Assembly site	MTAI				
	BD Number	BD-001964-03				
	MP Code (MPC)	569127C2XQUL				
	Part Number (CPN)	56912-MTAI-QUAL-SU				
<u>Misc.</u>	MSL information	1				
	Assembly Shipping Media (T/R, Tube/Tray)	Tube / T&R				
	Base Quantity Multiple (BQM)	100 / 4000				
	Reliability Site	MTAI				
	Paddle size	90 x 90 mils				
	Material	CDA194				
	DAP Surface Prep	Bare Cu				
	Treatment	BOT				
Lood Frama	Process	Stamped				
<u>Lead-Frame</u>	Lead-lock	No				
	Part Number	10100812				
	Lead Plating	Matte tin				
	Strip Size	MTAI standard				
	Strip Density	MTAI standard				
Bond Wire	Material	CuPdAu				
Die Attach	Part Number	QMI519				
<u>Die Attach</u>	Conductive	Yes				
MC	Part Number	G600V				
	Package Type	SOIC				
PKG	Pin/Ball Count	8				
	PKG width/size	150 mils				

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Standard Pb-free Solderability	J-STD-002D ; Perform 8 hour steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.	22	5	1	27	> 95% lead coverage	5	Standard Pb-free solderability is the requirement. SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5	30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5		5	30 bonds from a min. 5 devices.
Wire Sweep								Required for any reduction in wire bond thickness.
Physical Dimensions	Measure per JESD22 B100 and B108	10	0	3	30		5	
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5	

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Preconditioning - Required for surface mount devices MSL 1 @ 260 C	JESD22-A113. +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD- 020E for package type; Electrical test pre and post stress at +25°C.	231	15	3	738	0	15	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.
HAST	JESD22-A110. +130°C/85% RH for 96 hours or 110°C/85% RH for 264 hours. Electrical test pre and post stress at +25°C and hot temp. Max test temp at 85 C	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre- conditioning. Post-stress Electrical Test Window Time: Within 48 hours.
UHAST	JESD22-A118. +130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs. Electrical test pre and post stress at +25°C	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre- conditioning. Post-stress Electrical Test Window Time: Within 48 hours.

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Temp Cycle	JESD22-A10465°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress. Max test temp at 85 C	77	5	3	246	0	15	Spares should be properly identified. Use the parts which have gone through Pre- conditioning.